

The high resolution chemical profiles of Archean banded cherts and BIFs

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Archean banded cherts and banded iron formations were deep-sea sediments, therefore, they can be considered as recording tapes of the environmental variations at the time of sedimentation. In order to decode these records, we measured large amount of the samples by means of the Scanning X-ray Analytical Microscope and constructed the high resolution chemical profiles. We can detect some anomalous concentration layers of some elements, which may indicate environmental events occurred on the Archean Earth.